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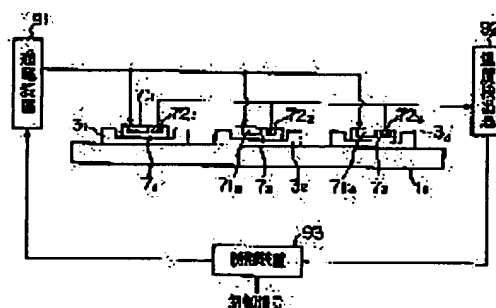
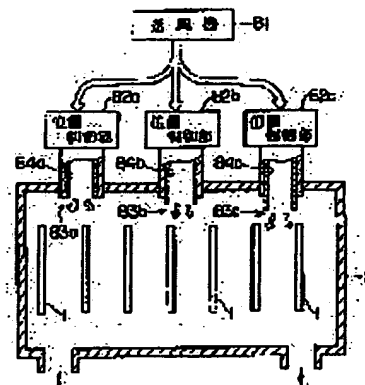
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(54) METHOD AND APPARATUS FOR BURN-IN

(57)Abstract:

PURPOSE: To control the temperature of individual semiconductor chips themselves with good accuracy and nearly uniformly by a method wherein temperature sensors are installed at individual semiconductor devices in the semiconductor chips themselves at the inside of the semiconductor devices, the sensors are monitored and opening positions of ventilation ports are set individually according to monitored results.

CONSTITUTION: A plurality of burn-in boards 1 are installed at the inside of a burn-in (high-temperature continuous operation) test container 6; semiconductor devices which are provided with semiconductor chips 71 to 73 at the inside are set on the boards. Integrated circuits 711 to 713 and diodes 721 to 723 for temperature detection use are formed on the semiconductor chips 71 to 73. The electric characteristic of the diodes 72 for temperature detection use is monitored individually by using a temperature detector 92. A control device 93 controls an electricity-feeding amount by 40 electricity-feeding device 91 on the basis of monitored results by the temperature detector 92 and controls opening positions of ventilation ports 83a to 83c via position control parts 82a to 82c. Thereby, the temperature of the individual chips themselves can be controlled with good accuracy and uniformly.



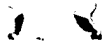
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